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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Obsolete
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I <sup>2</sup> C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	20
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 12x14b; D/A 4x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	24-VFQFN Exposed Pad
Supplier Device Package	24-QFN (3x3)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/silicon-labs/efm8lb12f64es0-b-qfn24r">https://www.e-xfl.com/product-detail/silicon-labs/efm8lb12f64es0-b-qfn24r</a>

## 1. Feature List

The EFM8LB1 device family are fully integrated, mixed-signal system-on-a-chip MCUs. Highlighted features are listed below.

- Core:
  - Pipelined CIP-51 Core
  - Fully compatible with standard 8051 instruction set
  - 70% of instructions execute in 1-2 clock cycles
  - 72 MHz maximum operating frequency
- Memory:
  - Up to 64 kB flash memory (63 kB user-accessible), in-system re-programmable from firmware in 512-byte sectors
  - Up to 4352 bytes RAM (including 256 bytes standard 8051 RAM and 4096 bytes on-chip XRAM)
- Power:
  - Internal LDO regulator for CPU core voltage
  - Power-on reset circuit and brownout detectors
- I/O: Up to 29 total multifunction I/O pins:
  - Up to 25 pins 5 V tolerant under bias
  - Selectable state retention through reset events
  - Flexible peripheral crossbar for peripheral routing
  - 5 mA source, 12.5 mA sink allows direct drive of LEDs
- Clock Sources:
  - Internal 72 MHz oscillator with accuracy of  $\pm 2\%$
  - Internal 24.5 MHz oscillator with  $\pm 2\%$  accuracy
  - Internal 80 kHz low-frequency oscillator
  - External CMOS clock option
  - External crystal/RC oscillator (up to 25 MHz)
- Analog:
  - 14/12/10-Bit Analog-to-Digital Converter (ADC)
  - Internal calibrated temperature sensor ( $\pm 3\text{ }^{\circ}\text{C}$ )
  - 4 x 12-Bit Digital-to-Analog Converters (DAC)
  - 2 x Low-current analog comparators with adjustable reference
- Communications and Digital Peripherals:
  - 2 x UART, up to 3 Mbaud
  - SPI™ Master / Slave, up to 12 Mbps
  - SMBus™/I2C™ Master / Slave, up to 400 kbps
  - I2C High-Speed Slave, up to 3.4 Mbps
  - 16-bit CRC unit, supporting automatic CRC of flash at 256-byte boundaries
  - 4 Configurable Logic Units
- Timers/Counters and PWM:
  - 6-channel Programmable Counter Array (PCA) supporting PWM, capture/compare, and frequency output modes
  - 6 x 16-bit general-purpose timers
  - Independent watchdog timer, clocked from the low frequency oscillator
- On-Chip, Non-Intrusive Debugging
  - Full memory and register inspection
  - Four hardware breakpoints, single-stepping
- Pre-programmed UART or SMBus bootloader

With on-chip power-on reset, voltage supply monitor, watchdog timer, and clock oscillator, the EFM8LB1 devices are truly standalone system-on-a-chip solutions. The flash memory is reprogrammable in-circuit, providing nonvolatile data storage and allowing field upgrades of the firmware. The on-chip debugging interface (C2) allows non-intrusive (uses no on-chip resources), full speed, in-circuit debugging using the production MCU installed in the final application. This debug logic supports inspection and modification of memory and registers, setting breakpoints, single stepping, and run and halt commands. All analog and digital peripherals are fully functional while debugging. Device operation is specified from 2.2 V up to a 3.6 V supply. Devices are AEC-Q100 qualified (pending) and available in 4x4 mm 32-pin QFN, 3x3 mm 24-pin QFN, 32-pin QFP, or 24-pin QSOP packages. All package options are lead-free and RoHS compliant.

## 2. Ordering Information

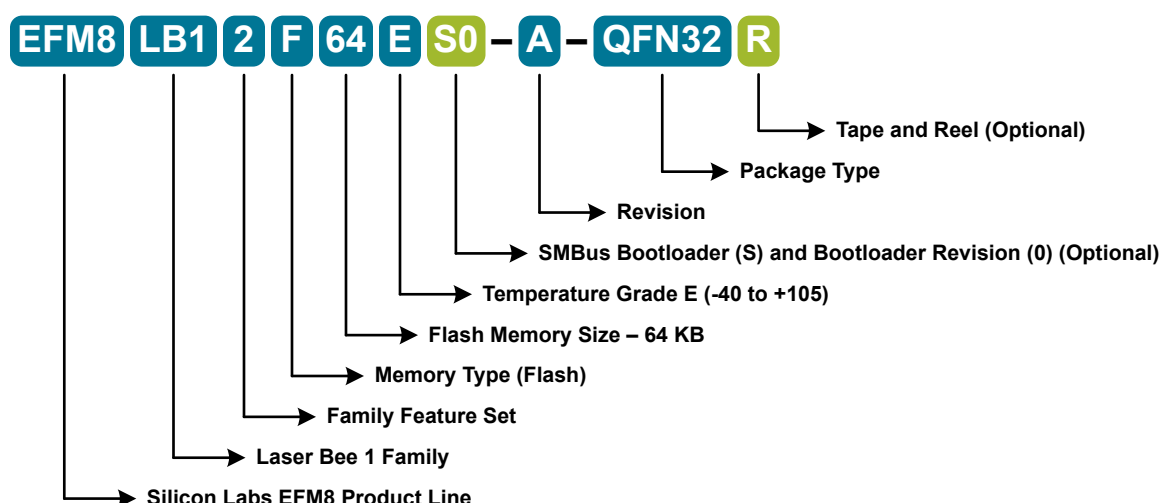


Figure 2.1. EFM8LB1 Part Numbering

All EFM8LB1 family members have the following features:

- CIP-51 Core running up to 72 MHz
- Three Internal Oscillators (72 MHz, 24.5 MHz and 80 kHz)
- SMBus
- I2C Slave
- SPI
- 2 UARTs
- 6-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- Six 16-bit Timers
- Four Configurable Logic Units
- 14-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, temperature sensor, channel sequencer, and direct-to-VRAM data transfer
- Two Analog Comparators
- 16-bit CRC Unit
- AEC-Q100 qualified (pending)

In addition to these features, each part number in the EFM8LB1 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Voltage DACs	Comparator 0 Inputs	Comparator 1 Inputs	Bootloader Type	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8LB12F64E-B-QFN32	64	4352	29	20	4	10	9	UART	Yes	-40 to +105 °C	QFN32
EFM8LB12F64E-B-QFP32	64	4352	28	20	4	10	9	UART	Yes	-40 to +105 °C	QFP32
EFM8LB12F64E-B-QFN24	64	4352	20	12	4	6	6	UART	Yes	-40 to +105 °C	QFN24

### 3.2 Power

All internal circuitry draws power from the VDD supply pin. External I/O pins are powered from the VIO supply voltage (or VDD on devices without a separate VIO connection), while most of the internal circuitry is supplied by an on-chip LDO regulator. Control over the device power can be achieved by enabling/disabling individual peripherals as needed. Each analog peripheral can be disabled when not in use and placed in low power mode. Digital peripherals, such as timers and serial buses, have their clocks gated off and draw little power when they are not in use.

**Table 3.1. Power Modes**

Power Mode	Details	Mode Entry	Wake-Up Sources
Normal	Core and all peripherals clocked and fully operational		
Idle	<ul style="list-style-type: none"> <li>Core halted</li> <li>All peripherals clocked and fully operational</li> <li>Code resumes execution on wake event</li> </ul>	Set IDLE bit in PCON0	Any interrupt
Suspend	<ul style="list-style-type: none"> <li>Core and peripheral clocks halted</li> <li>HFOSC0 and HFOSC1 oscillators stopped</li> <li>Regulator in normal bias mode for fast wake</li> <li>Timer 3 and 4 may clock from LFOSC0</li> <li>Code resumes execution on wake event</li> </ul>	<ol style="list-style-type: none"> <li>Switch SYSCLK to HFOSC0</li> <li>Set SUSPEND bit in PCON1</li> </ol>	<ul style="list-style-type: none"> <li>Timer 4 Event</li> <li>SPI0 Activity</li> <li>I2C0 Slave Activity</li> <li>Port Match Event</li> <li>Comparator 0 Falling Edge</li> <li>CLUn Interrupt-Enabled Event</li> </ul>
Stop	<ul style="list-style-type: none"> <li>All internal power nets shut down</li> <li>Pins retain state</li> <li>Exit on any reset source</li> </ul>	<ol style="list-style-type: none"> <li>Clear STOPCF bit in REG0CN</li> <li>Set STOP bit in PCON0</li> </ol>	Any reset source
Snooze	<ul style="list-style-type: none"> <li>Core and peripheral clocks halted</li> <li>HFOSC0 and HFOSC1 oscillators stopped</li> <li>Regulator in low bias current mode for energy savings</li> <li>Timer 3 and 4 may clock from LFOSC0</li> <li>Code resumes execution on wake event</li> </ul>	<ol style="list-style-type: none"> <li>Switch SYSCLK to HFOSC0</li> <li>Set SNOOZE bit in PCON1</li> </ol>	<ul style="list-style-type: none"> <li>Timer 4 Event</li> <li>SPI0 Activity</li> <li>I2C0 Slave Activity</li> <li>Port Match Event</li> <li>Comparator 0 Falling Edge</li> <li>CLUn Interrupt-Enabled Event</li> </ul>
Shutdown	<ul style="list-style-type: none"> <li>All internal power nets shut down</li> <li>Pins retain state</li> <li>Exit on pin or power-on reset</li> </ul>	<ol style="list-style-type: none"> <li>Set STOPCF bit in REG0CN</li> <li>Set STOP bit in PCON0</li> </ol>	<ul style="list-style-type: none"> <li>RSTb pin reset</li> <li>Power-on reset</li> </ul>

### 3.3 I/O

Digital and analog resources are externally available on the device's multi-purpose I/O pins. Port pins P0.0-P2.3 can be defined as general-purpose I/O (GPIO), assigned to one of the internal digital resources through the crossbar or dedicated channels, or assigned to an analog function. Port pins P2.4 to P3.7 can be used as GPIO. Additionally, the C2 Interface Data signal (C2D) is shared with P3.0 or P3.7, depending on the package option.

The port control block offers the following features:

- Up to 29 multi-functions I/O pins, supporting digital and analog functions.
- Flexible priority crossbar decoder for digital peripheral assignment.
- Two drive strength settings for each port.
- State retention feature allows pins to retain configuration through most reset sources.
- Two direct-pin interrupt sources with dedicated interrupt vectors (INT0 and INT1).
- Up to 24 direct-pin interrupt sources with shared interrupt vector (Port Match).

Bootloader	Pins for Bootload Communication
<b>Note:</b> 1. The STK uses these pins for another purpose, so there is a special SMBus bootloader build for the STK only included in <i>AN945: EFM8 Factory Bootloader User Guide</i> that uses P1.2 (SDA) and P1.3 (SCL).	

**Table 3.3. Summary of Pins for Bootload Mode Entry**

Device Package	Pin for Bootload Mode Entry
QFN32	P3.7 / C2D
QFP32	P3.7 / C2D
QFN24	P3.0 / C2D
QSOP24	P3.0 / C2D

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
ADC0 <sup>4</sup>	I <sub>ADC</sub>	High Speed Mode 1 Msps, 12-bit conversions Normal bias settings V <sub>DD</sub> = 3.0 V	—	1275	1700	μA
		Low Power Mode 350 ksps, 12-bit conversions Low power bias settings V <sub>DD</sub> = 3.0 V	—	390	530	μA
Internal ADC0 Reference <sup>5</sup>	I <sub>VREFFS</sub>	High Speed Mode	—	700	790	μA
		Low Power Mode	—	170	210	μA
On-chip Precision Reference	I <sub>VREFP</sub>		—	75	—	μA
Temperature Sensor	I <sub>TSENSE</sub>		—	68	120	μA
Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3) <sup>6</sup>	I <sub>DAC</sub>		—	125	—	μA
Comparators (CMP0, CMP1)	I <sub>CMP</sub>	CPMD = 11	—	0.5	—	μA
		CPMD = 10	—	3	—	μA
		CPMD = 01	—	10	—	μA
		CPMD = 00	—	25	—	μA
Comparator Reference	I <sub>CPREF</sub>		—	24	—	μA
Voltage Supply Monitor (VMON0)	I <sub>VMON</sub>		—	15	20	μA

**Note:**

1. Currents are additive. For example, where I<sub>DD</sub> is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
2. Includes supply current from internal LDO regulator, supply monitor, and High Frequency Oscillator.
3. Includes supply current from internal LDO regulator, supply monitor, and Low Frequency Oscillator.
4. ADC0 power excludes internal reference supply current.
5. The internal reference is enabled as-needed when operating the ADC in low power mode. Total ADC + Reference current will depend on sampling rate.
6. DAC supply current for each enabled DA and not including external load on pin.

## 4.1.9 ADC

Table 4.9. ADC

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N <sub>bits</sub>	14 Bit Mode	14			Bits
		12 Bit Mode	12			Bits
		10 Bit Mode	10			Bits
Throughput Rate (High Speed Mode)	f <sub>S</sub>	14 Bit Mode	—	—	900	ksps
		12 Bit Mode	—	—	1	Msps
		10 Bit Mode	—	—	1.125	Msps
Throughput Rate (Low Power Mode)	f <sub>S</sub>	14 Bit Mode	—	—	320	ksps
		12 Bit Mode	—	—	340	ksps
		10 Bit Mode	—	—	360	ksps
Tracking Time	t <sub>TRK</sub>	High Speed Mode	217.8 <sup>1</sup>	—	—	ns
		Low Power Mode	450	—	—	ns
Power-On Time	t <sub>PWR</sub>		1.2	—	—	μs
SAR Clock Frequency	f <sub>SAR</sub>	High Speed Mode	—	—	18.36	MHz
		Low Power Mode	—	—	12.25	MHz
Conversion Time <sup>2</sup>	t <sub>CNV</sub>	14-Bit Conversion, SAR Clock =18 MHz, System Clock = 72 MHz.	0.81			μs
		12-Bit Conversion, SAR Clock =18 MHz, System Clock = 72 MHz.	0.7			μs
		10-Bit Conversion, SAR Clock =18 MHz, System Clock = 72 MHz.	0.59			μs
Sample/Hold Capacitor	C <sub>SAR</sub>	Gain = 1	—	5.2	—	pF
		Gain = 0.75	—	3.9	—	pF
		Gain = 0.5	—	2.6	—	pF
		Gain = 0.25	—	1.3	—	pF
Input Pin Capacitance	C <sub>IN</sub>	High Quality Input	—	20	—	pF
		Normal Input	—	20	—	pF
Input Mux Impedance	R <sub>MUX</sub>	High Quality Input	—	330	—	Ω
		Normal Input	—	550	—	Ω
Voltage Reference Range	V <sub>REF</sub>		1	—	V <sub>IO</sub>	V
Input Voltage Range <sup>3</sup>	V <sub>IN</sub>		0	—	V <sub>REF</sub> / Gain	V

#### 4.1.11 Temperature Sensor

**Table 4.11. Temperature Sensor**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Uncalibrated Offset	$V_{OFF}$	$T_A = 0\text{ }^{\circ}\text{C}$	—	751	—	mV
Uncalibrated Offset Error <sup>1</sup>	$E_{OFF}$	$T_A = 0\text{ }^{\circ}\text{C}$	—	19	—	mV
Slope	M		—	2.82	—	mV/ $^{\circ}\text{C}$
Slope Error <sup>1</sup>	$E_M$		—	29	—	$\mu\text{V}/^{\circ}\text{C}$
Linearity	LIN	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	—	-0.1 to 0.15	—	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	—	-0.2 to 0.35	—	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	—	-0.4 to 0.8	—	$^{\circ}\text{C}$
Turn-on Time	$t_{ON}$		—	3.5	—	$\mu\text{s}$
Temp Sensor Error Using Typical Slope and Factory-Calibrated Offset <sup>2, 3</sup>	$E_{TOT}$	$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	-2.6	—	1.8	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	-2.9	—	2.7	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	-3.2	—	4.2	$^{\circ}\text{C}$

**Note:**

1. Represents one standard deviation from the mean.
2. The factory-calibrated offset value is stored in the read-only area of flash in locations 0xFFD4 (low byte) and 0xFFD5 (high byte). The 14-bit result represents the output of the ADC when sampling the temp sensor using the 1.65 V internal voltage reference.
3. The temp sensor error includes the offset calibration error, slope error, and linearity error. The values are based upon characterization and are not tested across temperature in production. The values represent three standard deviations above and below the mean. Additional information on achieving high measurement accuracy is available in AN929: Accurate Temperature Sensing with the EFM8 Laser Bee MCU Family.



### 4.1.13 Comparators

Table 4.13. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	$t_{RESP0}$	+100 mV Differential	—	100	—	ns
		-100 mV Differential	—	150	—	ns
Response Time, CPMD = 11 (Low- est Power)	$t_{RESP3}$	+100 mV Differential	—	1.5	—	μs
		-100 mV Differential	—	3.5	—	μs
Positive Hysteresis Mode 0 (CPMD = 00)	$HYS_{CP+}$	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysteresis Mode 0 (CPMD = 00)	$HYS_{CP-}$	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	-8	—	mV
		CPHYN = 10	—	-16	—	mV
		CPHYN = 11	—	-32	—	mV
Positive Hysteresis Mode 1 (CPMD = 01)	$HYS_{CP+}$	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysteresis Mode 1 (CPMD = 01)	$HYS_{CP-}$	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	-6	—	mV
		CPHYN = 10	—	-12	—	mV
		CPHYN = 11	—	-24	—	mV
Positive Hysteresis Mode 2 (CPMD = 10)	$HYS_{CP+}$	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysteresis Mode 2 (CPMD = 10)	$HYS_{CP-}$	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	-4.5	—	mV
		CPHYN = 10	—	-9	—	mV
		CPHYN = 11	—	-18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	$HYS_{CP+}$	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Negative Hysteresis Mode 3 (CPMD = 11)	HYS <sub>CP-</sub>	CPHYN = 00	—	-1.5	—	mV
		CPHYN = 01	—	-4	—	mV
		CPHYN = 10	—	-8	—	mV
		CPHYN = 11	—	-16	—	mV
Input Range (CP+ or CP-)	V <sub>IN</sub>		-0.25	—	V <sub>IO</sub> +0.25	V
Input Pin Capacitance	C <sub>CP</sub>		—	7.5	—	pF
Internal Reference DAC Resolution	N <sub>bits</sub>		6			bits
Common-Mode Rejection Ratio	CMRR <sub>CP</sub>		—	70	—	dB
Power Supply Rejection Ratio	PSRR <sub>CP</sub>		—	72	—	dB
Input Offset Voltage	V <sub>OFF</sub>	T <sub>A</sub> = 25 °C	-10	0	10	mV
Input Offset Tempco	TC <sub>OFF</sub>		—	3.5	—	μV/°

#### 4.1.14 Configurable Logic

**Table 4.14. Configurable Logic**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Propagation Delay	t <sub>DLY</sub>	Through single CLU Using an external pin	—	—	35.3	ns
		Through single CLU Using an internal connection	—	3	—	ns
Clocking Frequency	F <sub>CLK</sub>	1 or 2 CLUs Cascaded	—	—	73.5	MHz
		3 or 4 CLUs Cascaded	—	—	36.75	MHz

#### 4.1.16 SMBus

**Table 4.16. SMBus Peripheral Timing Performance (Master Mode)**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Standard Mode (100 kHz Class)</b>						
I2C Operating Frequency	$f_{I2C}$		0	—	$70^2$	kHz
SMBus Operating Frequency	$f_{SMB}$		$40^1$	—	$70^2$	kHz
Bus Free Time Between STOP and START Conditions	$t_{BUF}$		9.4	—	—	$\mu s$
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		4.7	—	—	$\mu s$
Repeated START Condition Setup Time	$t_{SU:STA}$		9.4	—	—	$\mu s$
STOP Condition Setup Time	$t_{SU:STO}$		9.4	—	—	$\mu s$
Data Hold Time	$t_{HD:DAT}$		0	—	—	$\mu s$
Data Setup Time	$t_{SU:DAT}$		4.7	—	—	$\mu s$
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	$t_{LOW}$		4.7	—	—	$\mu s$
Clock High Period	$t_{HIGH}$		9.4	—	$50^3$	$\mu s$
<b>Fast Mode (400 kHz Class)</b>						
I2C Operating Frequency	$f_{I2C}$		0	—	$256^2$	kHz
SMBus Operating Frequency	$f_{SMB}$		$40^1$	—	$256^2$	kHz
Bus Free Time Between STOP and START Conditions	$t_{BUF}$		2.6	—	—	$\mu s$
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		1.3	—	—	$\mu s$
Repeated START Condition Setup Time	$t_{SU:STA}$		2.6	—	—	$\mu s$
STOP Condition Setup Time	$t_{SU:STO}$		2.6	—	—	$\mu s$
Data Hold Time	$t_{HD:DAT}$		0	—	—	$\mu s$
Data Setup Time	$t_{SU:DAT}$		1.3	—	—	$\mu s$
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	$t_{LOW}$		1.3	—	—	$\mu s$
Clock High Period	$t_{HIGH}$		2.6	—	$50^3$	$\mu s$

**Note:**

1. The minimum SMBus frequency is limited by the maximum Clock High Period requirement of the SMBus specification.
2. The maximum I2C and SMBus frequencies are limited by the minimum Clock Low Period requirements of their respective specifications.
3. SMBus has a maximum requirement of 50  $\mu s$  for Clock High Period. Operating frequencies lower than 40 kHz will be longer than 50  $\mu s$ . I2C can support periods longer than 50  $\mu s$ .

### 4.3 Absolute Maximum Ratings

Stresses above those listed in [Table 4.19 Absolute Maximum Ratings on page 30](#) may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at <http://www.silabs.com/support/quality/pages/default.aspx>.

**Table 4.19. Absolute Maximum Ratings**

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	$T_{BIAS}$		-55	125	°C
Storage Temperature	$T_{STG}$		-65	150	°C
Voltage on VDD	$V_{DD}$		GND-0.3	4.2	V
Voltage on VIO <sup>2</sup>	$V_{IO}$		GND-0.3	$V_{DD}+0.3$	V
Voltage on I/O pins or RSTb, excluding P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	$V_{IN}$	$V_{IO} > 3.3\text{ V}$	GND-0.3	5.8	V
		$V_{IO} < 3.3\text{ V}$	GND-0.3	$V_{IO}+2.5$	V
Voltage on P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	$V_{IN}$		GND-0.3	$V_{DD}+0.3$	V
Total Current Sunk into Supply Pin	$I_{VDD}$		—	400	mA
Total Current Sourced out of Ground Pin	$I_{GND}$		400	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	$I_{IO}$		-100	100	mA
Operating Junction Temperature	$T_J$	$T_A = -40\text{ °C to }105\text{ °C}$	-40	130	°C

**Note:**

1. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.

## 5.2 Debug

The diagram below shows a typical connection diagram for the debug connections pins. The pin sharing resistors are only required if the functionality on the C2D (a GPIO pin) and the C2CK (RSTb) is routed to external circuitry. For example, if the RSTb pin is connected to an external switch with debouncing filter or if the GPIO sharing with the C2D pin is connected to an external circuit, the pin sharing resistors and connections to the debug adapter must be placed on the hardware. Otherwise, these components and connections can be omitted.

For more information on debug connections, see the example schematics and information available in AN127: "Pin Sharing Techniques for the C2 Interface." Application notes can be found on the Silicon Labs website (<http://www.silabs.com/8bit-appnotes>) or in Simplicity Studio.

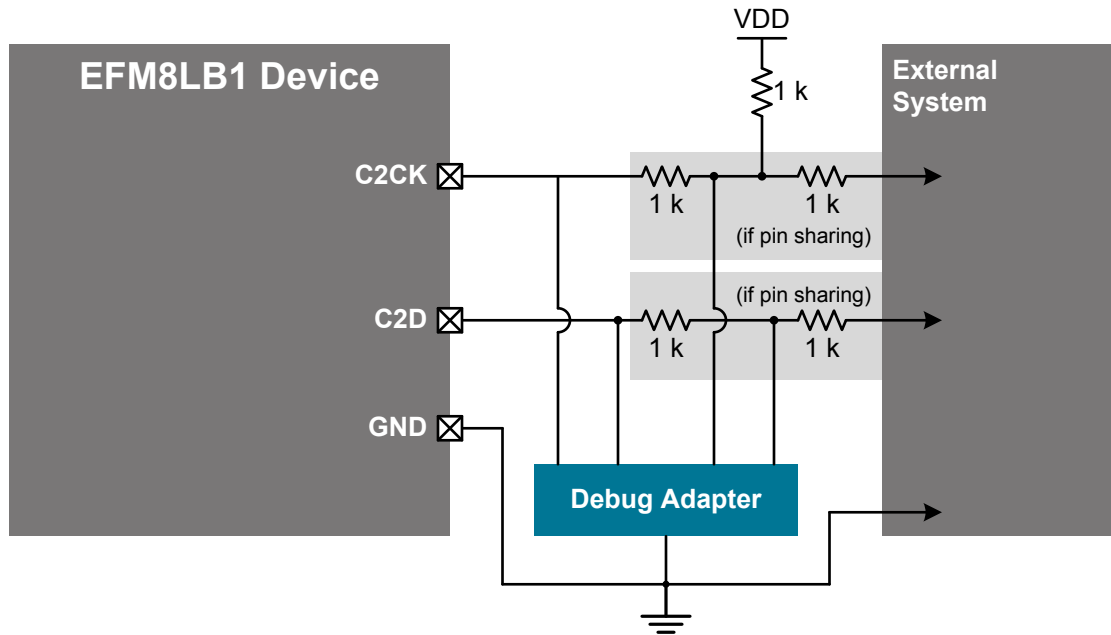


Figure 5.2. Debug Connection Diagram

## 5.3 Other Connections

Other components or connections may be required to meet the system-level requirements. Application Note AN203: "8-bit MCU Printed Circuit Board Design Notes" contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website ([www.silabs.com/8bit-appnotes](http://www.silabs.com/8bit-appnotes)).

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7 CMP0P.7 CMP0N.7
25	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU1OUT CLU0A.12 CLU1A.10 CLU2A.10 CLU3B.12	ADC0.6 CMP0P.6 CMP0N.6 CMP1P.1 CMP1N.1
26	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.0 CMP1N.0
27	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4
28	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9 CLU3B.11	ADC0.3 CMP0P.3 CMP0N.3

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
11	P2.1	Multifunction I/O	Yes	P2MAT.1 CLU1B.14 CLU2A.15 CLU3B.15	DAC1
12	P2.0	Multifunction I/O	Yes	P2MAT.0 CLU1A.14 CLU2A.14 CLU3B.14	DAC0
13	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.12 CMP1P.6 CMP1N.6
14	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU3OUT CLU0A.15 CLU1B.12 CLU2A.12	ADC0.11 CMP1P.5 CMP1N.5
15	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13	ADC0.10 CMP1P.4 CMP1N.4
16	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12	ADC0.9 CMP1P.3 CMP1N.3
17	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
18	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8
19	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7
20	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU0A.12 CLU1A.10 CLU2A.10 CLU3B.12	ADC0.6
21	P0.7	Multifunction I/O	Yes	P0MAT.7 INT0.7 INT1.7 CLU1OUT CLU0B.11 CLU1B.9 CLU3A.11	ADC0.5 CMP0P.5 CMP0N.5 CMP1P.1 CMP1N.1
22	P0.6	Multifunction I/O	Yes	P0MAT.6 CNVSTR INT0.6 INT1.6 CLU0A.11 CLU1B.8 CLU3A.10	ADC0.4 CMP0P.4 CMP0N.4 CMP1P.0 CMP1N.0
23	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9 CLU3B.11	ADC0.3 CMP0P.3 CMP0N.3



Dimension	Min	Max
<b>Note:</b> <ol style="list-style-type: none"> <li>1. All dimensions shown are in millimeters (mm) unless otherwise noted.</li> <li>2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.</li> <li>3. This Land Pattern Design is based on the IPC-7351 guidelines.</li> <li>4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05mm.</li> <li>5. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.</li> <li>6. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.</li> <li>7. The stencil thickness should be 0.125 mm (5 mils).</li> <li>8. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.</li> <li>9. A 2 x 2 array of 1.10 mm square openings on a 1.30 mm pitch should be used for the center pad.</li> <li>10. A No-Clean, Type-3 solder paste is recommended.</li> <li>11. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.</li> </ol>		

### 7.3 QFN32 Package Marking



Figure 7.3. QFN32 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

Dimension	Min	Typ	Max
e	0.40 BSC		
e1	0.45 BSC		
J	1.60	1.70	1.80
K	1.60	1.70	1.80
L	0.35	0.40	0.45
L1	0.25	0.30	0.35
aaa	—	0.10	—
bbb	—	0.10	—
ccc	—	0.08	—
ddd	—	0.1	—
eee	—	0.1	—

**Note:**

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-248 but includes custom features which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

## 10. QSOP24 Package Specifications

### 10.1 QSOP24 Package Dimensions

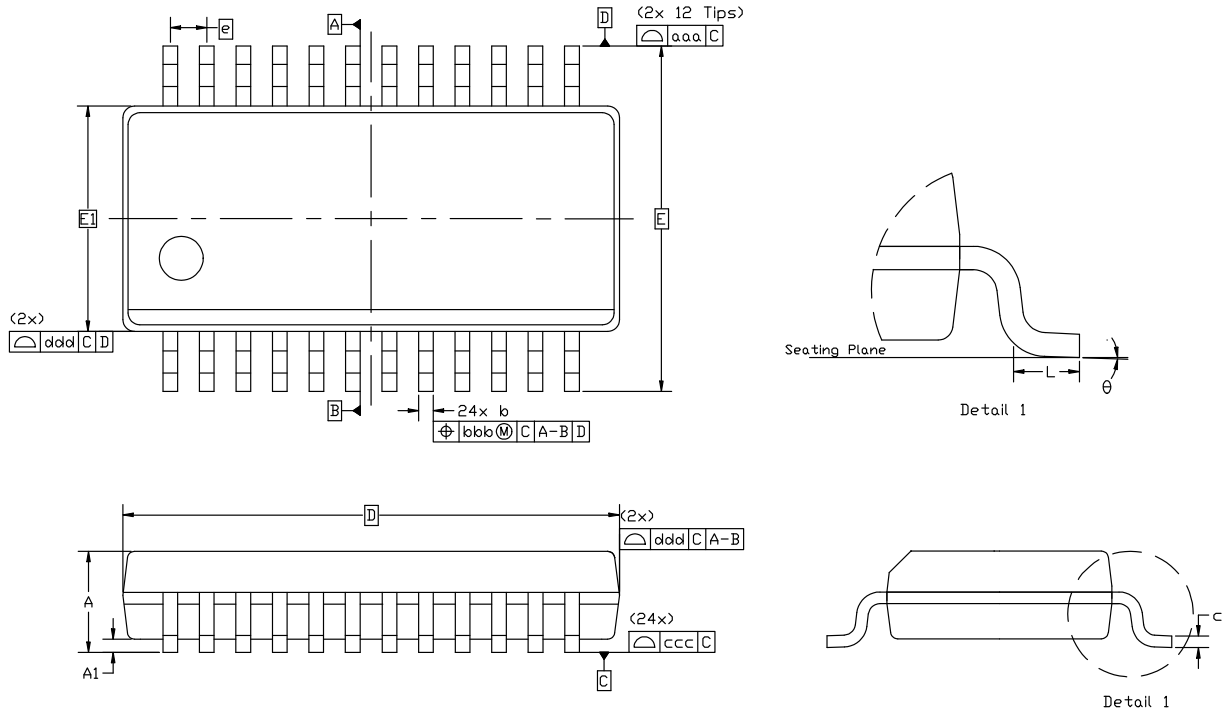


Figure 10.1. QSOP24 Package Drawing

Table 10.1. QSOP24 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.75
A1	0.10	—	0.25
b	0.20	—	0.30
c	0.10	—	0.25
D	8.65 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	0.635 BSC		
L	0.40	—	1.27
theta	0°	—	8°

## 11. Revision History

### 11.1 Revision 1.01

October 21st, 2016

Updated QFN24 center pad stencil description.

### 11.2 Revision 1.0

September 6th, 2016

Updated part numbers to revision B.

Updated many specifications with full characterization data.

Added a note regarding which DACs are available to [Table 2.1 Product Selection Guide on page 2](#).

Added specifications for [4.1.16 SMBus](#).

Added bootloader pinout information to [3.10 Bootloader](#).

Added CRC Calculation Time to [4.1.4 Flash Memory](#).

### 11.3 Revision 0.5

February 10th, 2016

Updated [Figure 5.2 Debug Connection Diagram on page 32](#) to move the pull-up resistor on C2D / RSTb to after the series resistor instead of before.

Added S0 devices and information about the SMBus bootloader in [3.10 Bootloader](#).

Added a reference to *AN945: EFM8 Factory Bootloader User Guide* in [3.10 Bootloader](#).

Added mention of the pre-programmed bootloaders in [1. Feature List](#).

Updated all part numbers to revision B.

Added the C oscillator, which is now available on revision B.

Adjusted C1, C2, X2, Y2, and Y1 maximums for [7.2 QFN32 PCB Land Pattern](#).

Adjusted package markings for QFN32 and QSOP24 packages.

Filled in TBD minimum and maximum values for DAC Differential Nonlinearity in [Table 4.12 DACs on page 24](#).

### 11.4 Revision 0.4

Updated specification tables based on current device characterization status and production test limits.

Added bootloader section.

Added typical connection diagrams.

Corrected CLU connections in pin function tables.

### 11.5 Revision 0.3

Added information on the bootloader to [3.10 Bootloader](#).

Updated some characterization TBD values.

### 11.6 Revision 0.1

Initial release.

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# Table of Contents

<b>1. Feature List</b>	<b>1</b>
<b>2. Ordering Information</b>	<b>2</b>
<b>3. System Overview</b>	<b>4</b>
3.1 Introduction	4
3.2 Power	5
3.3 I/O	5
3.4 Clocking	6
3.5 Counters/Timers and PWM	6
3.6 Communications and Other Digital Peripherals	7
3.7 Analog	10
3.8 Reset Sources	11
3.9 Debugging	11
3.10 Bootloader	12
<b>4. Electrical Specifications</b>	<b>14</b>
4.1 Electrical Characteristics	14
4.1.1 Recommended Operating Conditions	14
4.1.2 Power Consumption	15
4.1.3 Reset and Supply Monitor	17
4.1.4 Flash Memory	17
4.1.5 Power Management Timing	18
4.1.6 Internal Oscillators	18
4.1.7 External Clock Input	19
4.1.8 Crystal Oscillator	19
4.1.9 ADC	20
4.1.10 Voltage Reference	22
4.1.11 Temperature Sensor	23
4.1.12 DACs	24
4.1.13 Comparators	25
4.1.14 Configurable Logic	26
4.1.15 Port I/O	27
4.1.16 SMBus	28
4.2 Thermal Conditions	29
4.3 Absolute Maximum Ratings	30
<b>5. Typical Connection Diagrams</b>	<b>31</b>
5.1 Power	31
5.2 Debug	32
5.3 Other Connections	32
<b>6. Pin Definitions</b>	<b>33</b>
6.1 EFM8LB1x-QFN32 Pin Definitions	33